

**Search Notes****Application/Control No.**

10/005,193

**Examiner**

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**Applicant(s)/Patent under Reexamination**

CHEN ET AL.

**Art Unit**

2162

**SEARCHED**

Class	Subclass	Date	Examiner
707	1, 2, 3, 5, 101, 104.1	6/11/2005	FE
703	27	6/11/2005	FE
706	23	6/11/2005	FE
709	203, 223	6/11/2005	FE
713	176	6/11/2005	FE

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Search	6/11/2005	FE
IEEE Xplore Search	6/11/2005	FE
ACM Digital Library Search	6/11/2005	FE